

Search Notes

Application/Control No.

10/690,318

Examiner

Eric B. Chen

Applicant(s)/Patent under
Reexamination

MUI ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
430	5	6/21/2005	EC
438	5,9,14,16	6/21/2005	EC
438	714	6/21/2005	EC
438	719-721	6/21/2005	EC
438	723,724	6/21/2005	EC
438	740,743	6/21/2005	EC
438	744	6/21/2005	EC
216	60,67,70	6/21/2005	EC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Performed inventor search for double patenting	6/20/2005	EC
EAST search	6/21/2005	EC